

Resource Summary Report

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University of Louisville Micro/Nano Technology Center Imaging and Characterization Core Facility

RRID:SCR_028481

Type: Tool

Proper Citation

University of Louisville Micro/Nano Technology Center Imaging and Characterization Core Facility (RRID:SCR_028481)

Resource Information

URL: <https://research.louisville.edu/centers-institutes-labs/core-facilities/imaging-characterization-core>

Proper Citation: University of Louisville Micro/Nano Technology Center Imaging and Characterization Core Facility (RRID:SCR_028481)

Description: Core provides advanced imaging and characterization capabilities including SEM, AFM, and infrared thermal microscopy supporting research in engineering, materials science, biology, and more. Offers imaging and characterization for semiconductors and/or other Micro/Nano scale devices.

Synonyms: University of Louisville Micro/Nano Technology Center Imaging and Characterization Core, Micro/Nano Technology Center Imaging and Characterization Core

Resource Type: core facility, access service resource, service resource

Keywords: ABRF, imaging services, SEM, AFM, microscopy, infrared thermal microscopy,

Resource Name: University of Louisville Micro/Nano Technology Center Imaging and Characterization Core Facility

Resource ID: SCR_028481

Alternate IDs: ABRF_5798

Alternate URLs: <https://coremarketplace.org/?FacilityID=5798&citation=1>

Record Creation Time: 20260522T053906+0000

Record Last Update: 20260811T043841+0000

Ratings and Alerts

No rating or validation information has been found for University of Louisville Micro/Nano Technology Center Imaging and Characterization Core Facility.

No alerts have been found for University of Louisville Micro/Nano Technology Center Imaging and Characterization Core Facility.

Data and Source Information

Source: [SciCrunch Registry](#)

Usage and Citation Metrics

We have not found any literature mentions for this resource.